

Search Notes

Application/Control No.

10/784,302

Examiner

Hiep Nguyen

Applicant(s)/Patent under
Reexamination

YAMAMOTO ET AL.

Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
327	112	06.10.05	112
	322	—	—
323	285	—	—
	284	—	—
327	577	—	—

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	06.10.05	112
See attachment		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner